

April 2000

FQA16N50

500V N-Channel MOSFET

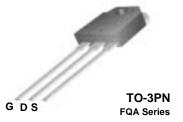
General Description

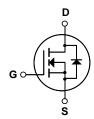
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply, power factor correction, electronic lamp ballast based on half bridge.

Features

- 16A, 500V, $R_{DS(on)}$ = 0.32 Ω @V_{GS} = 10 V Low gate charge (typical 60 nC)
- Low Crss (typical 35 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQA16N50	Units
V _{DSS}	Drain-Source Voltage		500	V
I _D	Drain Current - Continuous (T _C = 25	°C)	16	А
	- Continuous (T _C = 10	0°C)	10	А
I _{DM}	Drain Current - Pulsed	(Note 1)	64	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	980	mJ
I _{AR}	Avalanche Current	(Note 1)	16	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	20	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_D	Power Dissipation (T _C = 25°C) - Derate above 25°C		200	W
			1.59	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.63	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

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Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA		500			V
ΔBV_{DSS}	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 2	5°C		0.53		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 500 V, V _{GS} = 0 V				1	μА
		V _{DS} = 400 V, T _C = 125°C			-	10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-	-100	nA
On Chr	aracteristics	,				•	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 8.0 A			0.25	0.32	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 8.0 A (No	te 4)		14		S
	Output Capacitance	f = 1 0 MHz			325	420	pF pF
Coss	Output Capacitance	f = 1.0 MHz			325	420	pF
C _{rss}	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz			325 35	420 45	
C _{rss}	' '	f = 1.0 MHz					pF
C _{rss}	Reverse Transfer Capacitance						pF
C _{rss} Switch t _{d(on)}	Reverse Transfer Capacitance	f = 1.0 MHz $V_{DD} = 250 \text{ V}, I_D = 16 \text{ A},$ $R_G = 25 \Omega$			35	45	pF pF
C _{rss} Switch t _{d(on)}	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time	$V_{DD} = 250 \text{ V}, I_{D} = 16 \text{ A},$ $R_{G} = 25 \Omega$			35 45	100	pF pF
	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time	$V_{DD} = 250 \text{ V}, I_{D} = 16 \text{ A},$ $R_{G} = 25 \Omega$	÷ 4, 5)		35 45 180	100 370	pF pF
$\begin{array}{c} \textbf{C}_{\text{rss}} \\ \hline \textbf{Switch} \\ \textbf{t}_{\text{d(on)}} \\ \textbf{t}_{\text{r}} \\ \textbf{t}_{\text{d(off)}} \\ \textbf{t}_{\text{f}} \\ \textbf{Q}_{\text{g}} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time	$V_{DD} = 250 \text{ V}, I_{D} = 16 \text{ A},$ $R_{G} = 25 \Omega$	÷ 4, 5)		35 45 180 130	100 370 270	pF pF ns ns ns ns
$\begin{array}{c} \textbf{C}_{\text{rss}} \\ \hline \textbf{Switch} \\ \textbf{t}_{\text{d(on)}} \\ \textbf{t}_{\text{r}} \\ \textbf{t}_{\text{d(off)}} \\ \textbf{t}_{\text{f}} \\ \textbf{Q}_{\text{g}} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	V_{DD} = 250 V, I_{D} = 16 A, R_{G} = 25 Ω (Note	÷ 4, 5)	 	35 45 180 130 100	100 370 270 210	pF pF ns ns ns ns
$\begin{array}{c} \textbf{C}_{\text{rss}} \\ \hline \\ \textbf{Switch} \\ \textbf{t}_{\text{d(on)}} \\ \textbf{t}_{\text{r}} \\ \textbf{t}_{\text{d(off)}} \\ \textbf{t}_{\text{f}} \\ \textbf{Q}_{\text{g}} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	$V_{DD} = 250 \text{ V}, I_D = 16 \text{ A},$ $R_G = 25 \Omega$ (Note $V_{DS} = 400 \text{ V}, I_D = 16 \text{ A},$ $V_{GS} = 10 \text{ V}$	÷ 4, 5)	 	35 45 180 130 100 60	100 370 270 210 75	pF pF ns ns ns ns nc nC
$\begin{array}{c} C_{rss} \\ \hline \textbf{Switch} \\ t_{d(on)} \\ t_r \\ t_{d(off)} \\ t_f \\ C_g \\ C_{gs} \\ C_{gd} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 250 \text{ V}, I_D = 16 \text{ A},$ $R_G = 25 \Omega$ (Note $V_{DS} = 400 \text{ V}, I_D = 16 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note		 	35 45 180 130 100 60 14	100 370 270 210 75	pF pF ns ns
$\begin{array}{c} C_{rss} \\ \hline \textbf{Switch} \\ t_{d(on)} \\ t_r \\ t_{d(off)} \\ t_f \\ C_g \\ C_{gs} \\ C_{gd} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$V_{DD} = 250 \text{ V}, I_D = 16 \text{ A},$ $R_G = 25 \Omega$ (Note $V_{DS} = 400 \text{ V}, I_D = 16 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note and Maximum Ratings		 	35 45 180 130 100 60 14	100 370 270 210 75	pF pF ns ns ns ns
$\begin{array}{c} \textbf{C}_{rss} \\ \textbf{Switch} \\ \textbf{t}_{d(on)} \\ \textbf{t}_{r} \\ \textbf{t}_{d(off)} \\ \textbf{t}_{f} \\ \textbf{Q}_{g} \\ \textbf{Q}_{gs} \\ \textbf{Q}_{gd} \\ \\ \textbf{Drain-S} \\ \textbf{I}_{S} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	V_{DD} = 250 V, I_D = 16 A, R_G = 25 Ω (Note V_{DS} = 400 V, I_D = 16 A, V_{GS} = 10 V (Note and Maximum Ratings and Forward Current		 	35 45 180 130 100 60 14 28	100 370 270 210 75 	pF pF pF
C _{rss} Switch t _{d(on)} t _r t _{d(off)} t _f Q _g Q _{gs} Q _{gd} Drain-S	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode	V_{DD} = 250 V, I_D = 16 A, R_G = 25 Ω (Note V_{DS} = 400 V, I_D = 16 A, V_{GS} = 10 V (Note and Maximum Ratings and Forward Current		 	35 180 130 100 60 14 28	100 370 270 210 75 	pF pF ns ns ns nc nC
$\begin{array}{c} \textbf{C}_{rss} \\ \textbf{Switch} \\ \textbf{t}_{d(on)} \\ \textbf{t}_{r} \\ \textbf{t}_{d(off)} \\ \textbf{t}_{f} \\ \textbf{Q}_{g} \\ \textbf{Q}_{gs} \\ \textbf{Q}_{gd} \\ \\ \textbf{Drain-S} \\ \textbf{I}_{S} \\ \end{array}$	Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics au Maximum Continuous Drain-Source Diode F	V_{DD} = 250 V, I_{D} = 16 A, R_{G} = 25 Ω (Note V_{DS} = 400 V, I_{D} = 16 A, V_{GS} = 10 V (Note and Maximum Ratings and Forward Current		 	35 45 180 130 100 60 14 28	100 370 270 210 75 	pF pF pF ns ns ns nc nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 6.9mH, I_{AS} = 16A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 16A, di/dt \leq 2004/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

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Typical Characteristics

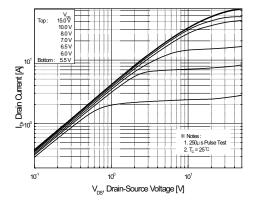


Figure 1. On-Region Characteristics

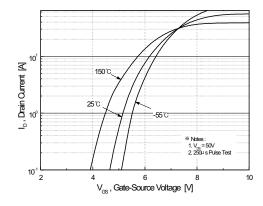


Figure 2. Transfer Characteristics

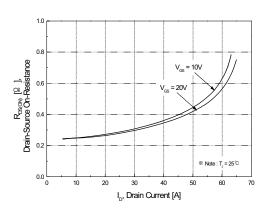


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

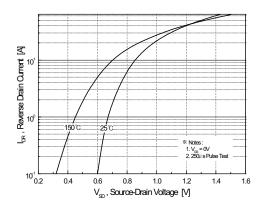


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

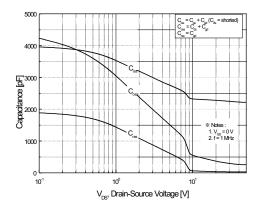


Figure 5. Capacitance Characteristics

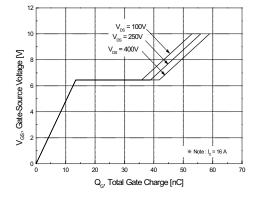


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

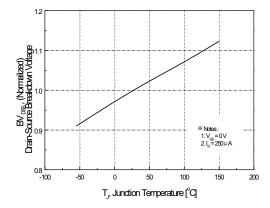


Figure 7. Breakdown Voltage Variation vs. Temperature

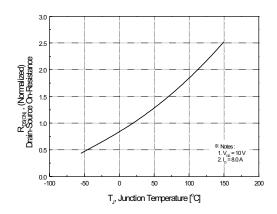


Figure 8. On-Resistance Variation vs. Temperature

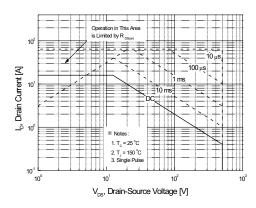


Figure 9. Maximum Safe Operating Area

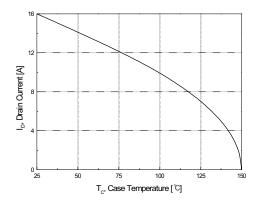


Figure 10. Maximum Drain Current vs. Case Temperature

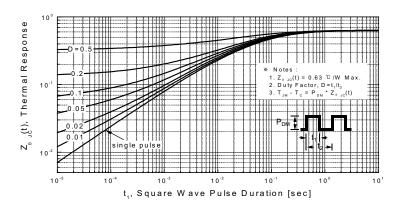
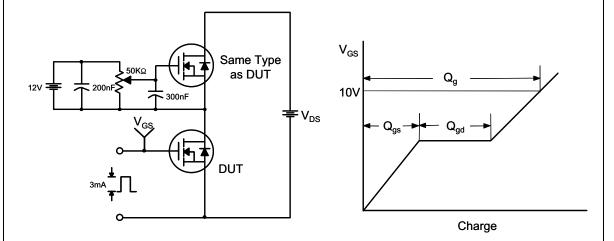


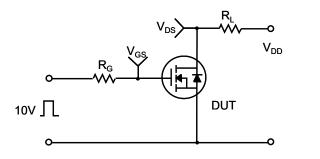
Figure 11. Transient Thermal Response Curve

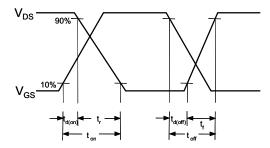
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Gate Charge Test Circuit & Waveform

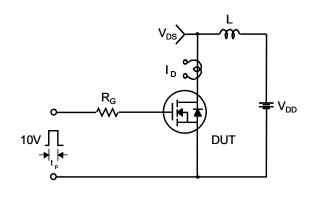


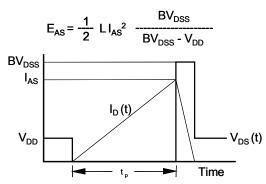
Resistive Switching Test Circuit & Waveforms



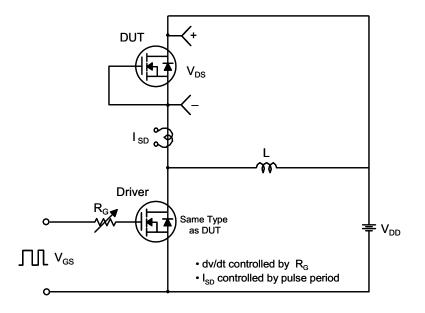


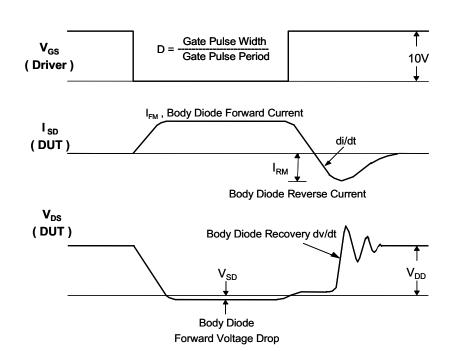
Unclamped Inductive Switching Test Circuit & Waveforms



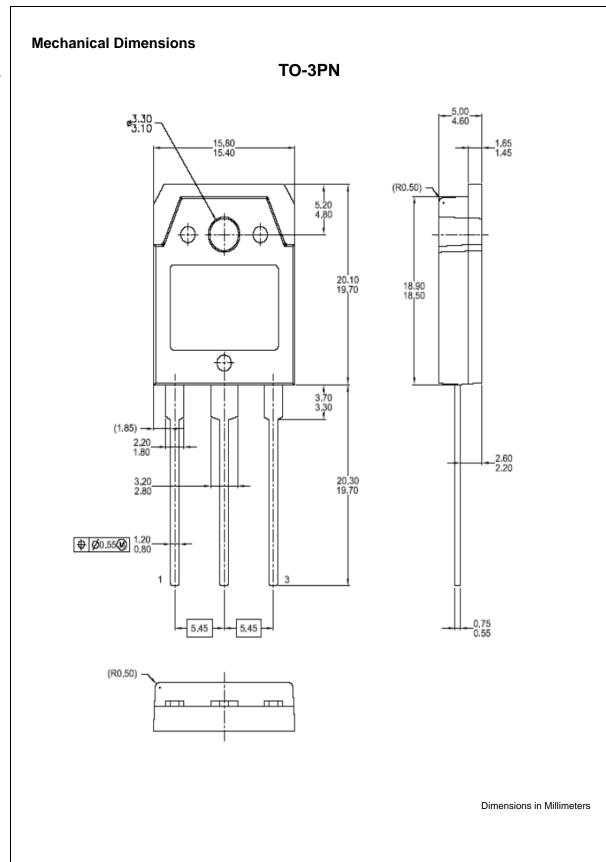


Peak Diode Recovery dv/dt Test Circuit & Waveforms





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